Search Notes

Applicati n/Contr I N .	Applicant(s)/Patent under Reexaminati n	
10/789,886	MEYER ET AL.	
Examiner	Art Unit	
Frederick C. Nicolas	3754	

SEARCHED					
Class	Subclass	Date	Examiner		
222	566-568	8/27/2006	FN		
222	173,181.2	8/27/2006	FN		
222	196,196.1	8/27/2006	FN		
222	575,180	8/27/2006	FN		
222	610,475	8/27/2006	FN		
222	465.1,183	8/27/2006	FN		
222	105	8/27/2006	FN		
224	148.2,274	8/27/2006	FN		
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248	310,318	8/27/2006	FN		
248	311.2	8/27/2006	FN		
248	205.1	8/27/2006	FN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
222	568	8/27/2006	FN		
222	105	8/27/2006	FN		
222	181.2	8/27/2006	FN		
222/465.1 222/566 222/575 224/148.4		8/27/2006	FN		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Updated search thru east including text search. Interference search also conducted.	8/27/2006	FN
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